Special Issue

Advances in Low-Frequency Noise Measurements

Message from the Guest Editor

This Special Issue focuses on the latest advances in the field of low-frequency noise measurements, with a particular focus on experimental results relating to new and advanced electron devices, applications in the field of quality and reliability, measurement methodologies, and dedicated instrumentation. Topics of interest include, but are not limited to, the following:

- Low-frequency noise in electron devices and circuits;
- Low-frequency noise in advanced materials;
- Low-frequency noise in optical devices;
- Low-frequency noise measurement methodologies and instrumentation;
- Application of low-frequency noise to the evaluation of the quality and reliability of electron devices and systems;
- Low-frequency noise simulation and modeling.

Please click here to find information! Welcome to contribute!

Guest Editor

Prof. Dr. Carmine Ciofi Department of Engineering, Messina University, 98166 Messina, Italy

Deadline for manuscript submissions

closed (31 January 2022)



Electronics

an Open Access Journal by MDPI

Impact Factor 2.6 CiteScore 6.1



mdpi.com/si/30153

Electronics Editorial Office MDPI, Grosspeteranlage 5 4052 Basel, Switzerland Tel: +41 61 683 77 34 electronics@mdpi.com

mdpi.com/journal/

electronics





an Open Access Journal by MDPI

Impact Factor 2.6 CiteScore 6.1



electronics



About the Journal

Message from the Editor-in-Chief

Electronics is a multidisciplinary journal designed to appeal to a diverse audience of research scientists, practitioners, and developers in academia and industry. The journal is devoted to fast publication of latest technological breakthroughs, cutting-edge developments, and timely reviews of current and emerging technologies related to the broad field of electronics. Experimental and theoretical results are published as regular peer-reviewed articles or as articles within Special Issues guest-edited by leading experts in selected topics of interest.

Editor-in-Chief

Prof. Dr. Flavio Canavero Department of Electronics and Telecommunications, Politecnico di Torino, 10129 Torino, Italy

Author Benefits

High Visibility:

indexed within Scopus, SCIE (Web of Science), CAPlus / SciFinder, Inspec, Ei Compendex and other databases.

Journal Rank:

JCR - Q2 (Physics, Applied) / CiteScore - Q1 (Electrical and Electronic Engineering)

Rapid Publication:

manuscripts are peer-reviewed and a first decision is provided to authors approximately 16.4 days after submission; acceptance to publication is undertaken in 2.4 days (median values for papers published in this journal in the second half of 2024).